Fab Section	Test

General Product Information

Vendor Supplier	Zeiss
Model	NanoFab
Vintage	2015
Serial No	
Asset Description	Focus Ion Beam Mill
Software Version	Windows
CIM	NONE
Process	Focus Ion Beam Mill

Hardware Configuration

System Type	Description	Quantity
Main System	FIB tool designed for Packaging and Deep cuts	1
Factory Interface	NONE	
Options System		
Others		
Handler System	Manual	